

Notice of References Cited

Application/Control No.

09/606,934

Applicant(s)/Patent Under

Reexamination

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Examiner

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Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,317,609	11-2001	Alperovich et al.	455/556.1
	B	US-6,538,692	03-2003	Niwa, Mayumi	348/231.1
	C	US-6,181,954	01-2001	Monroe et al.	455/557
	D	US-6,522,889	02-2003	Aarnio, Ari	455/456.5
	E	US-6,392,697	05-2002	Tanaka et al.	348/220.1
	F	US-6,167,469	12-2000	Safai et al.	710/62
	G	US-6,069,648	05-2000	Suso et al.	348/14.02
	H	US-6,466,202	10-2002	Suso et al.	345/169
	I	US-6,567,661	05-2003	McDonnell et al.	340/870.07
	J	US-6,535,243	03-2003	Tullis, Barclay J.	348/207.1
	K	US-5,978,016	11-1999	Lourette et al.	348/64
	L	US-5,706,097	01-1998	Schelling et al.	358/296
	M	US-5,806,005	09-1998	Hull et al.	455/566

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 1189424 A1	03-2002	European Patent	EVANS, TRACY J	H04N 01/00
	O	EP 930770 A2	07-1999	European Patent	AOKI et al.	H04N 01/00
	P	WO 9948276 A1	09-1999	World Intellect	ANDERSON et al.	H04N 01/00
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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